

## REMARKS

Examiner Guerrero is thanked for the courtesy of returning a call the week of June 12 regarding an Office communication dated 5/22/2006 that stated the reply filed on February 28, 2006 was not fully responsive. During the discussion with Examiner Guerrero, the current scope of claim 1 (reproduced below for convenience) was discussed with respect to the specific example illustrated at Figures 13 and 14 (FIG. 14 reproduced below for convenience).

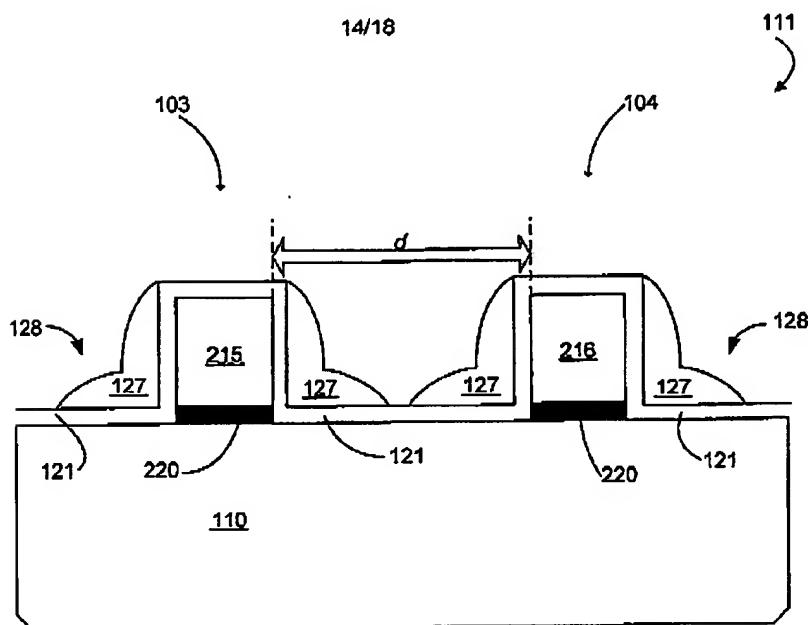


FIG. 14

## Claim 1:

1. A method for fabricating sidewall spacers in the manufacture of an integrated circuit device, comprising:  
forming a dielectric spacer layer overlying a gate structure formed on a semiconductor substrate; and

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etching said dielectric spacer layer without the use of a sacrificial forming spacer to form L-shaped spacers for the gate structure, the L-shaped spacers including a horizontal portion having a thickness that varies gradually to provide for an average thickness of the horizontal portion that is 50 to 85 percent of a maximum thickness of the horizontal portion.

Specifically discussed was how Figure 13 illustrates a dielectric spacer layer 122 that is etched without the use of a sacrificial forming spacer to form L-shaped spacer for the gate structure as illustrated in FIG. 14. The horizontal portion has a thickness that varies gradually to provide for an average thickness of the horizontal portion that is 50- 85 percent of a maximum thickness of the horizontal portion.

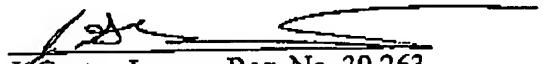
Further discussed with Examiner Guerrero was how the horizontal portion of the L-shaped spacer has a maximum thickness, which in the embodiment of FIG. 14 is illustrated to be that part of the horizontal portion that is immediately adjacent to a vertical portion of the L-shaped spacer. It was agreed that claim 1 was clear as presented, in that since there can be only one maximum thickness with respect to the horizontal portion of the L-shaped spacer.

The Attorney of Record, Mr. Larson, agreed to include this discussion relating to the maximum thickness in these remarks.

Based on these comments, and by agreement with Ms. Guerrero, entry of the amendments and consideration of the reply dated 2/28/2006 is respectfully requested.

Respectfully submitted,

6-22-08  
Date

  
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